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ON Semiconductor NTMS4800NR2G

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Distributor of ON Semiconductor: Excellent Integrated System Limited Datasheet of NTMS4800NR2G - MOSFET N-CH 30V 4.9A 8-SOIC Contact us: sales@integrated-circuit.com Website: www.integrated-circuit.com

NTMS4800N

Power MOSFET 30 V, 8 A, N-Channel, SOIC-8

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- SOIC-8 Surface Mount Package Saves Board Space
- This is a Pb-Free Device

Applications

- DC-DC Converters
- Printers

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter Symbol Value Uni					Unit
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Voltage	°			±20	V
Continuous Drain		T _A = 25°C	V _{GS} I _D	6.4	А
Current R _{0JA} (Note 1)		T _A = 70°C		5.1	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	1.29	W
Continuous Drain		T _A = 25°C	I _D	4.9	А
Current $R_{\theta JA}$ (Note 2)	Steady	$T_A = 70^{\circ}C$		3.9	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	$T_A = 25^{\circ}C$	PD	0.75	W
Continuous Drain		T _A = 25°C	۱ _D	8.0	А
Current R _{θJA} , t < 10 s (Note 1)		$T_A = 70^{\circ}C$		6.4	
Power Dissipation $R_{\theta JA}$, t < 10 s (Note 1)		T _A = 25°C	P _D	2.0	W
Pulsed Drain Current $T_A = 25^{\circ}C$, $t_p = 10 \ \mu s$			I _{DM}	32	А
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to +150	°C
Source Current (Body Diode)			۱ _S	2.0	А
$ Single Pulse Drain-to-Source Avalanche Energy \\ (T_J = 25^\circ C, V_{DD} = 30 V, V_{GS} = 10 V, \\ I_L = 11 A_{pk}, L = 1.0 \text{ mH}, R_G = 25 \Omega) $			E _{AS}	60.5	mJ
Lead Temperature for Soldering Purposes $(1/8'' \text{ from case for t} = 10 \text{ s})$			ΤL	260	°C

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	97	°C/W
Junction-to-Ambient – t < 10 s (Note 1)	$R_{\theta JA}$	62.5	
Junction-to-Foot (Drain)	$R_{\theta JF}$	25	
Junction-to-Ambient - Steady State (Note 2)	R _{0.1A}	167	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability. 1. Surface-mounted on FR4 board using 1 in sq pad, 1 oz Cu

2. Surface-mounted on FR4 board using the minimum recommended pad size

1

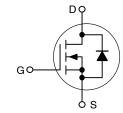


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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX	
30 V	20 mΩ @ 10 V	8 A	
50 V	27 mΩ @ 4.5 V	07	





MARKING DIAGRAM/ **PIN ASSIGNMENT** Source 🛥 Drain Source 📼 ⊐ Drain SO-8 Source 📼 🛥 Drain **CASE 751** Gate -Drain STYLE 12 Top View 4800N = Device Code = Assembly Location Α = Year v = Work Week WW = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS4800NR2G	SOIC-8 (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.



NTMS4800N

ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I _D = 250 µA		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				26		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V_{GS} = 0 V, V_{DS} = 24 V	T _J = 25°C T ₁ = 125°C			1.0 10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =				±100	nA
ON CHARACTERISTICS (Note 3)	.033	103 - 1, 103					
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μA	1.5		3.0	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	7.5 A		12.5	20	mΩ
		V _{GS} = 4.5 V, I _D =	6.5 A		20	27	
Forward Transconductance	9 FS	V _{DS} = 1.5 V, I _D =	7.5 A		21		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	ICE					
Input Capacitance	C _{iss}	T			940		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MHz,	V _{DS} = 15 V		225		
Reverse Transfer Capacitance	C _{rss}	· · · · · · · · · · · · · · · · · · ·			125		
Total Gate Charge	Q _{G(TOT)}	-			7.7		nC
Threshold Gate Charge	Q _{G(TH)}				1.1		
Gate-to-Source Charge	Q _{GS}	V _{GS} = 4.5 V, V _{DS} = 15 V	V, I _D = 7.5 A		3.3		
Gate-to-Drain Charge	Q _{GD}				3.2		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V, I _D = 7.5 A			15.2		nC
SWITCHING CHARACTERISTICS (No	ote 4)						
Turn–On Delay Time	t _{d(on)}				9.4		ns
Rise Time	t _r	V _{GS} = 10 V, V _{DS} = 15 V,			4.0		
Turn–Off Delay Time	t _{d(off)}	$I_{\rm D} = 1.0 \text{ A}, \text{ R}_{\rm G} =$	6.0 Ω [΄]		21		
Fall Time	t _f				6.5		
DRAIN-SOURCE DIODE CHARACTE	RISTICS						
Forward Diode Voltage	V _{SD}		$T_J = 25^{\circ}C$		0.75	1.0	V
		$V_{GS} = 0 V, I_S = 2.0 A$	T _J = 125°C		0.59		
Reverse Recovery Time	t _{RR}				17.8		ns
Charge Time	t _a	V_{GS} = 0 V, d_{IS}/d_t = 100 A/µs, I_S = 2.0 A			8.3		
Discharge Time	t _b				9.5		
Reverse Recovery Charge	Q _{RR}				8.0		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S	- T _A = 25°C			0.66		nH
Drain Inductance	L _D				0.20		nH
Gate Inductance	L _G				1.5		nH
Gate Resistance	R _G				1.5	3.0	Ω

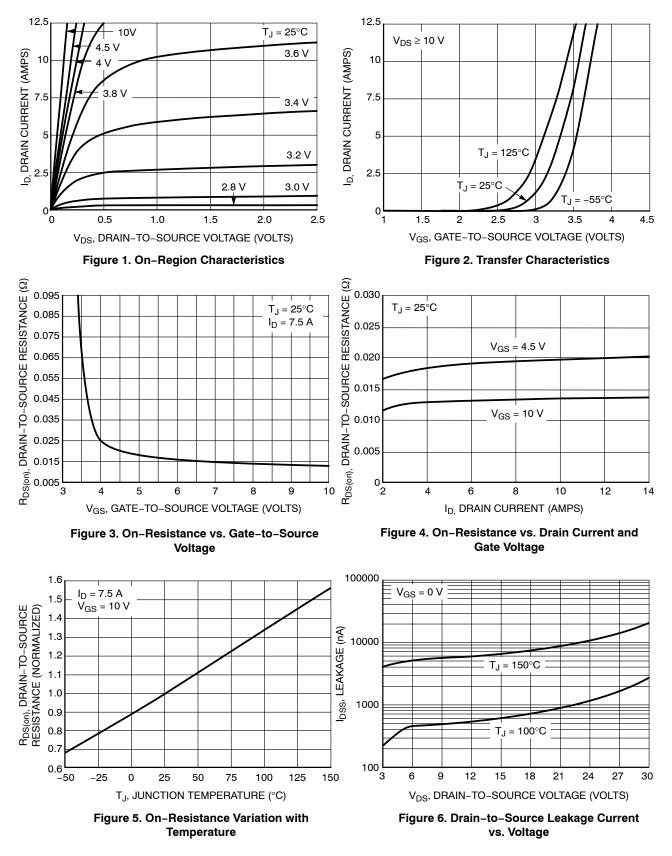
Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.



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TYPICAL PERFORMANCE CURVES

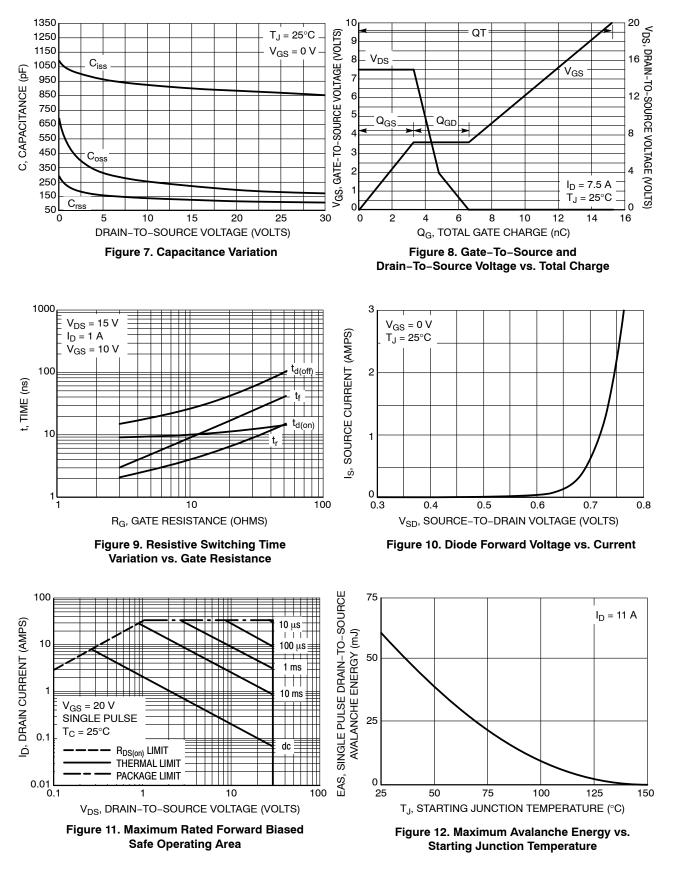




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NTMS4800N

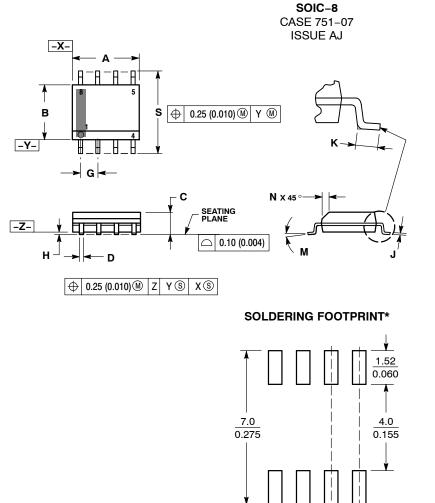
TYPICAL PERFORMANCE CURVES





NTMS4800N

PACKAGE DIMENSIONS



0.6

0.024

NOTES

- IDIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
 DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- 4
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE. DIMENSION D DOES NOT INCLUDE DAMBAR 5. PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT
- MAXIMUM MATERIAL CONDITION. 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07. 6

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
в	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
н	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
К	0.40	1.27	0.016	0.050
м	0 °	8 °	0 °	8 °
Ν	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

TYLE 1	2.
	SOURCE
2.	SOURCE
З.	SOURCE
4.	GATE
5.	DRAIN
6.	DRAIN
7.	DRAIN
8.	DRAIN

s

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

1.270

0.050

SCALE 6:1

 $\left(\frac{\text{mm}}{\text{inches}}\right)$

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